

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	98	("6251598" "6475753" "6342581" "6410709" "6420526" "6433139" "6409664" "6461828" "6359194" "5364880" "5440054" "5891628" "6300492" "6567752" "20020046004" "20050152836" "6107919" "6532426" "6904388" "7065433" "20040158367" "20040162705" "5749900" "6035233" "6144878" "5573908" "5599919" "5633161" "5783422" "5798266" "5817783" "5837453" "5962246" "6025126" "6025137" "6100031" "6238877" "6251597" "6251629" "6255075" "6261802" "6268470" "6274361" "6274719" "6277595" "6287521" "6287765" "6287807" "6287854" "6288218").pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:17
L5	74	((integrated adj circuit) or (ic near chip)) and prognostic and stress and fail\$3	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:17
L7	1	L5 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:17
L9	15	L5 and "702"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:17
L11	18	("5166592" "5220259" "5355060" "5473230" "5677611" "5734242" "5912539" "6014598" "6330140").PN. OR ("6646397").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:17
L13	181851	((integrated adj circuit) or ic) and (prognostic or fail\$3 or degradient)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:17
L15	28840	((integrated adj circuit) or ic) and (prognostic or fail\$3 or degradi\$5) and stress	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:17
L17	1130	L15 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:17
L19	5	((integrated adj circuit) or ic) and ((prognostic or fail\$3 or degradi\$5)near cell) and (operation\$3 near stress)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:17
L21	51	L15 and "324"/763.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:18

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L23	59	("20020133767" "20020133769" "20020133770" "4032949" "4455495" "4534014" "4592025" "4707806" "5110754" "5235550" "5254943" "5296402" "5301143" "5313424" "5345110" "5352945" "5424652" "5428311" "5440240" "5457400" "5539235" "5539699" "5563832" "5590069" "5600171" "5606193" "5617366" "5619469" "5677917" "5768288" "5867505" "5895962" "5896398" "5919269" "5944845" "5982189" "5991220" "6002620" "6008523" "6016265" "6021078" "6025129" "6118138" "6127837" "6190972" "6194738" "6212114" "6233182" "6255837" "6269035" "6292009" "6324657" "6343366" "6353563" "6365421" "6611458" "6630685" "6829737" "6839873").PN. OR ("7119568").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:18
L25	7	("4542340" "5656511" "5804975").PN. OR ("6348806").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:18
L27	24	("5294883" "5332973" "5371457" "5483170" "5554941" "5670892" "5712857" "5731700" "5757203" "5869977").PN. OR ("6140832").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:18
L29	4	("5889408" "6140832" "6714032" "6734028").PN. OR ("6873171").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:18
L31	4	("5889408" "6140832" "6714032" "6734028").PN. OR ("6873171").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:18
L33	486	((integrated adj circuit) or ic) and (prognostic or fail\$3 or degrad\$5) and stress and (wearout or (life near time))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:18
L35	68	L33 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:18
L37	17	("4904946" "5023561" "5420513" "5594349").PN. OR ("6047243").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:18
L39	11	("4386389" "5233161" "5966021").PN. OR ("6215324").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:18
L41	52	((integrated adj circuit) or ic) and ((prognostic or fail\$3 or degrad\$5) near cell)and stress and (wearout or (life near time))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:18
L45	194	integrated adj circuit and failure and stress and indicator.clm.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:19
L47	20	L45 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:19

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L49	3	("5719800" "6282625" "6359624").PN. OR ("7005871").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L51	38	324/763,765.cds. and stress and ((life near time) or wearout) and fail\$3 and ((integrated adj circuit) or ic)	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L53	113	324/760,763,765.cds. and stress and (lifetime or wearout) and fail\$3 and ((integrated adj circuit) or ic)	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L55	19	("4243937" "5307385" "5650336" "5798649" "5877419" "5999011" "6020753" "6047247" "6239603" "6255707" "6275059" "6633177" "6684353" "6724214" "6867580" "6047247" "6198301" "6524872" "6587994" "6620639" "6724214").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L57	12	("5587665" "5625288" "6136619" "6169694" "6535014").PN. OR ("6724214").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L59	21	("3961251" "4243937" "4336495" "4719411" "4743841" "4782283" "4970454" "5703381" "6049218").PN. OR ("6239603").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L61	7	("4542340" "5656511" "5804975").PN. OR ("6348806").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L63	14	("5594349" "5600578" "6043102" "6049213").PN. OR ("6326792").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L65	11	("4386389" "5233161" "5966021").PN. OR ("6215324").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L67	5	("4786865" "5396169").PN. OR ("5841293").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L69	50	("4483629" "4739258" "4918385" "5057441" "5099196" "5202626" "5233161" "5294882" "5381087").PN. OR ("5625288").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L71	12	("5587665" "5625288" "6136619" "6169694" "6535014").PN. OR ("6724214").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L73	32	("3389336" "3825828" "4135153" "4357703" "4513418" "4701920" "4749947" "4833395" "5039602" "5065091" "5095267" "5099196" "5107208" "5150044" "5254940" "5260949" "5341096" "5363381" "5381087" "5428626" "5477139" "5477545" "5625288" "5729151").PN. OR ("6005407").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L75	32	("4465971" "4697140").PN. OR ("4833395").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L77	14	("4123704" "4207791" "4553109" "4724380" "5006787" "5099196").PN. OR ("5202626").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L79	29	("3474530" "4213087" "4483629" "4652812" "4739258" "4816895" "4897709" "5148259" "5264377" "5291142").PN. OR ("5497076").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19
L81	32	("3748579" "3943442" "4420722" "4483629" "4739258" "4799021" "4855672" "Re32625").PN. OR ("5030905").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:19

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L83	118	((integrated adj circuit) or ic) with (bist or (built adj in adj self adj test)) and (pass or fail\$3) and (dut or (device near under near test))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L85	25	L83 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L87	845	((integrated adj circuit) or ic) with (bist or (built adj in adj self adj test)) and (pass or fail\$3)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L89	98	L87 and "324"/\$.ccls.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L91	2	("6937047").PN.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2007/03/02 08:20
L93	10	("5392293" "5581563" "5726997" "5757203" "5929650" "5949798" "6144214" "6400171" "6593765").PN. OR ("6930500").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:20
L95	16	("5268635" "5270655").PN. OR ("5570035").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:20
L97	12	((integrated adj circuit) or ic) and (fail\$3 near probabil\$4) and stress and (wearout or (life near time))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L99	3	((integrated adj circuit) or ic) with (fail\$3 near probabil\$4) and (wearout or (life near time))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L101	1	((integrated adj circuit) or ic) with (fail\$3 near probabil\$4) and wearout	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L103	205	(threshold near5 voltage) near5 radiat\$4 and (transistor or MOS or PMOS) and compar\$5	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20

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L105	84	L103 and test\$4	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L107	142	L103 and (test\$4 or measur\$4)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/03/02 08:20
L109	1	("4011471").PN. OR ("6600241").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2007/03/02 08:20